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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re U.S. Patent Application

Luc Dewaele

Examiner: Gail Kaplan Verbitsky

Group Art Unit: 2859

Serial Number: 10/088,206

Attorney Docket: DEWA3001/JEK

Filed: July 9, 2002

For: METHOD AND DEVICE FOR MONITORING THE WEAR OF A RAPIER BAND

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant herewith submits a PTO-1449 form listing the documents mentioned in the International Search Report established in PCT/EP00/08886 of which this application is the U.S. national phase (35 U.S.C. 371).

A Notice of Acceptance of application under 35 U.S.C. 371 was mailed to Applicant on July 24, 2002 and confirms that a copy of the International Search Report and the references cited in the International Search Report have been received in this application. In accordance with MPEP 609, the Examiner should have considered the documents mentioned in the International Search Report.

The Examiner did not acknowledge that the documents mentioned in the International Search Report have been considered and the accompanying PTO-1449 form is submitted herewith to ensure that the documents mentioned in the International Search Report (all of "background" interest) are mentioned on the face of any patent to be granted from this application.

A fee is not required because the documents are already in the file of this application and presumably were considered by the Examiner.

Respectfully submitted,
BACON & THOMAS, PLLC


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Date: September 5, 2003

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Sheet 1 of 1

B/O Form 1449		Atty. Docket Number DEWA3001/JEK	Serial Number 10/088,206
U.S. Department of Commerce Patent and Trademark Office			
Information Disclosure Statement by Applicant			
Applicant LUC DEWAELE		Filing Date July 9, 2002	
Group 2859			

U.S. Patent Documents

Examiner Initial		Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate

Foreign Patent Documents

Examiner Initial		Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
							Yes	No
		05 156548 A	Dec. 1991	Japan				X
		0 533 046 A	Mar. 1993	EPO				X
		0 341 522 A	Nov. 1989	EPO				X

Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

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Examiner	Date Considered
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EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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